

BULT118

HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTORS

- STMicroelectronics PREFERRED SALESTYPE
- NPN TRANSISTOR
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

APPLICATIONS:

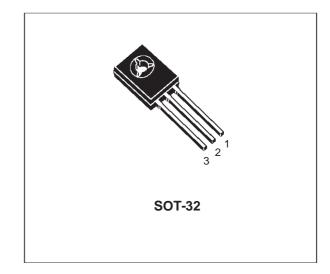
- ELECTRONIC BALLASTS FOR FLUORESCENT LIGHTING
- FLYBACK AND FORWARD SINGLE TRANSISTOR LOW POWER CONVERTERS

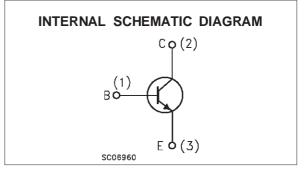
DESCRIPTION

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and medium voltage capability.

It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
VCES	Collector-Emitter Voltage (V _{BE} = 0)	700	V
Vceo	Collector-Emitter Voltage (I _B = 0)	400	V
V _{EBO}	Emitter-Base Voltage (I _C = 0)	9	V
lc	Collector Current	2	A
Ісм	Collector Peak Current (t _p < 5 ms)	4	A
Ι _Β	Base Current	1	A
I _{BM}	Base Peak Current (t _p < 5 ms)	2	A
Ptot	Total Dissipation at $T_c = 25$ °C	45	W
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

THERMAL DATA

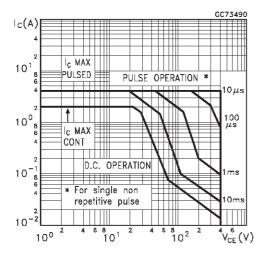
R _{thj-case}	Thermal	Resistance	Junction-Case	Max	2.77	°C/W
$R_{thj-amb}$	Thermal	Resistance	Junction-Ambient	Max	80	°C/W

ELECTRICAL CHARACTERISTICS ($T_{case} = 25 \,^{\circ}C$ unless otherwise specified)

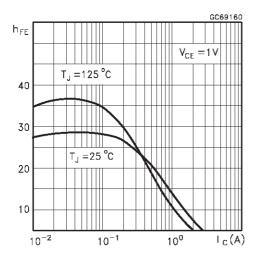
Symbol	Parameter	Test Co	onditions	Min.	Тур.	Max.	Unit
I _{CES}	Collector Cut-off Current ($V_{BE} = 0$)	V _{CE} = 700 V V _{CE} = 700 V	$T_{j} = 125 \ ^{o}C$			100 500	μΑ μΑ
V _{EBO}	Emitter-Base Voltage	I _E = 10 mA		9			V
$V_{CEO(sus)}^{*}$	Collector-Emitter Sustaining Voltage (I _B = 0)	I _C = 100 mA	L = 25 mH	400			V
I _{CEO}	Collector-Emitter Leakage Current	V _{CE} = 400 V				250	μA
VCE(sat)*	Collector-Emitter Saturation Voltage	$I_{C} = 0.5 A$ $I_{C} = 1 A$ $I_{C} = 2 A$	I _B = 0.1 A I _B = 0.2 A I _B = 0.4 A			0.5 1 1.5	V V V
V _{BE(sat)} *	Base-Emitter Saturation Voltage	$I_{C} = 0.5 A$ $I_{C} = 1 A$ $I_{C} = 2 A$	$I_{B} = 0.1 A$ $I_{B} = 0.2 A$ $I_{B} = 0.4 A$			1.0 1.2 1.3	V V V
h _{FE} *	DC Current Gain	$I_{C} = 10 \text{ mA}$ $I_{C} = 0.5 \text{ A}$ $I_{C} = 2 \text{ A}$	$V_{CE} = 5 V$ $V_{CE} = 5 V$ $V_{CE} = 5 V$	10 10 8		50	
tr t _s t _f	RESISTIVE LOAD Rise Time Storage Time Fall Time	Vcc = 125 V I _{B1} = 0.2 A	-		0.4 3.2 0.25	0.7 4.5 0.4	μs μs μs
t _s t _f	INDUCTIVE LOAD Storage Time Fall Time	$\begin{array}{l} I_{C} = 1 \ A \\ V_{BE} = -5 \ V \\ V_{clamp} = 300 \ V \end{array}$	I _{B1} = 0.2 A L = 50 mH		0.8 0.16		μs μs

* Pulsed: Pulse duration = 300 ms, duty cycle 1.5 %

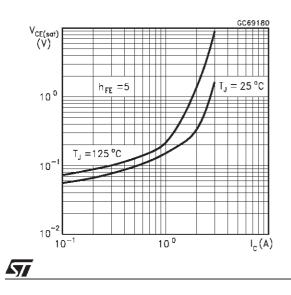
Safe Operating Areas



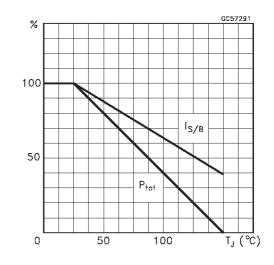
DC Current Gain



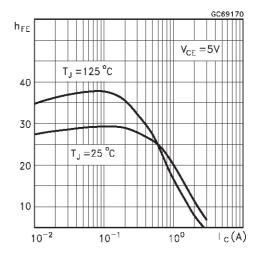
Collector Emitter Saturation Voltage



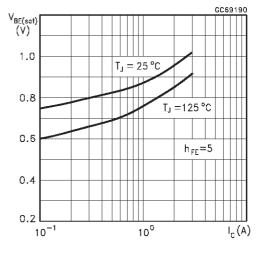
Derating Curve



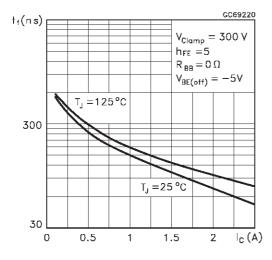
DC Current Gain



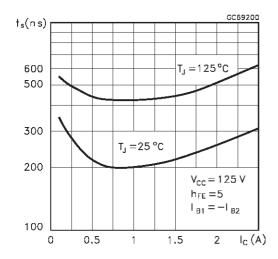




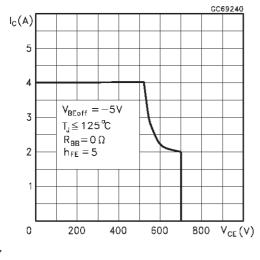
Inductive Fall Time



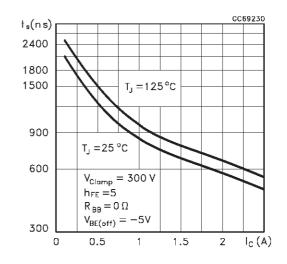
Resistive Fall Time

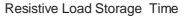


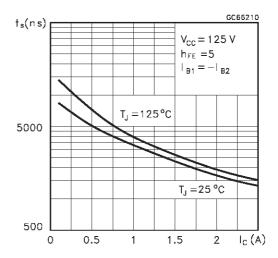
Reverse Biased SOA



Inductive Storage Time







57

Figure 1: Inductive Load Switching Test Circuits.

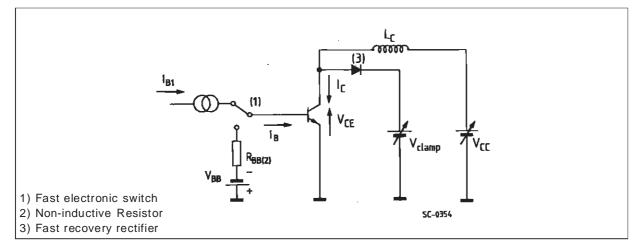
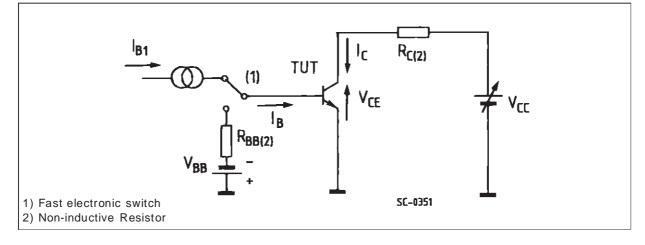
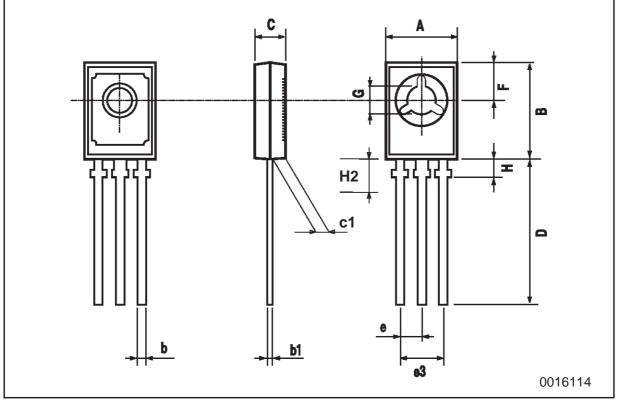


Figure 2: Resistive Load Switching Test Circuits.



DIM.	mm			inch			
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	7.4		7.8	0.291		0.307	
В	10.5		10.8	0.413		0.445	
b	0.7		0.9	0.028		0.035	
b1	0.49		0.75	0.019		0.030	
С	2.4		2.7	0.040		0.106	
c1	1.0		1.3	0.039		0.050	
D	15.4		16.0	0.606		0.629	
е		2.2			0.087		
e3	4.15		4.65	0.163		0.183	
F		3.8			0.150		
G	3		3.2	0.118		0.126	
Н			2.54			0.100	





57

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57